

2~4 GHz Low Noise Amplifier Chip

AS3105AA-A

Datasheet

V1.0

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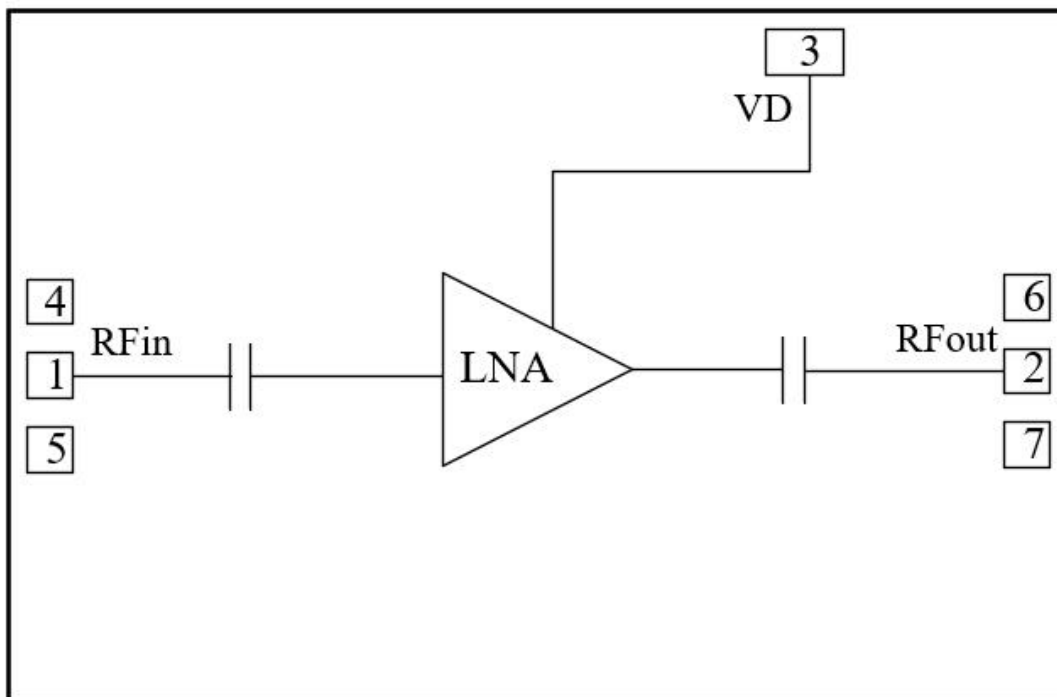
### 1. Product Features

- Frequency Range: 2~4 GHz
- Small Signal Gain: 33.5 dB
- Noise Figure: 0.4 dB (typical)
- Output P1dB: 21 dBm
- Bias Condition: VDD = 5.0 V, IDQ = 109 mA
- Chip Size: 1.50 mm × 1.20 mm × 0.10 mm

### 2. Functional Overview

This chip is a low noise amplifier operating from 2 to 4 GHz. It operates from a single +5.0 V supply. At a bias current of 109 mA, it provides a gain of 33.5 dB, output P1dB of 21 dBm, and a typical noise figure of 0.4 dB. The chip features 50  $\Omega$  port impedance and is grounded through the backside metal.

### 3. Block Diagram



## 4. Typical Applications

Suitable for communications, radar and other applications.

## 5. Electrical Parameters

### 5.1 RF Characteristics

Unless otherwise specified, all electrical characteristics are measured under conditions:  $V_D = 5.0$  V,  $I_{DQ} = 109$  mA, small-signal  $P_{in} = -40$  dBm,  $T_A = +25$  ° C, 50  $\Omega$  system, continuous wave.

Parameter	Symbol	Min.	Typ.	Max.	Unit	Remarks (Conditions)
Frequency Range	RF Range	2		4	GHz	
Input Return Loss	IRL		20		dB	
Output Return Loss	ORL		15		dB	
Small Signal Gain	Gain					
2 GHz			32.5		dB	
3 GHz			33.5		dB	
4 GHz			33.5		dB	
Gain Flatness	$\Delta G$		$\pm 0.5$		dB	@2~4GHz
Reverse Isolation	Isolation		43		dB	
Noise Figure	NF					
2 GHz			0.3		dB	
3 GHz			0.3		dB	
4 GHz			0.4		dB	
Gain Variation vs Temperature						
2 GHz			$\pm 0.8$		dB	
3 GHz			$\pm 0.8$		dB	-55°C, +25°C, +125°C
4 GHz			$\pm 0.8$		dB	
Output 1 dB Compression Point	OP1dB					
2 GHz			21		dBm	
3 GHz			21		dBm	
4 GHz			21		dBm	

## 5.2 DC Characteristics

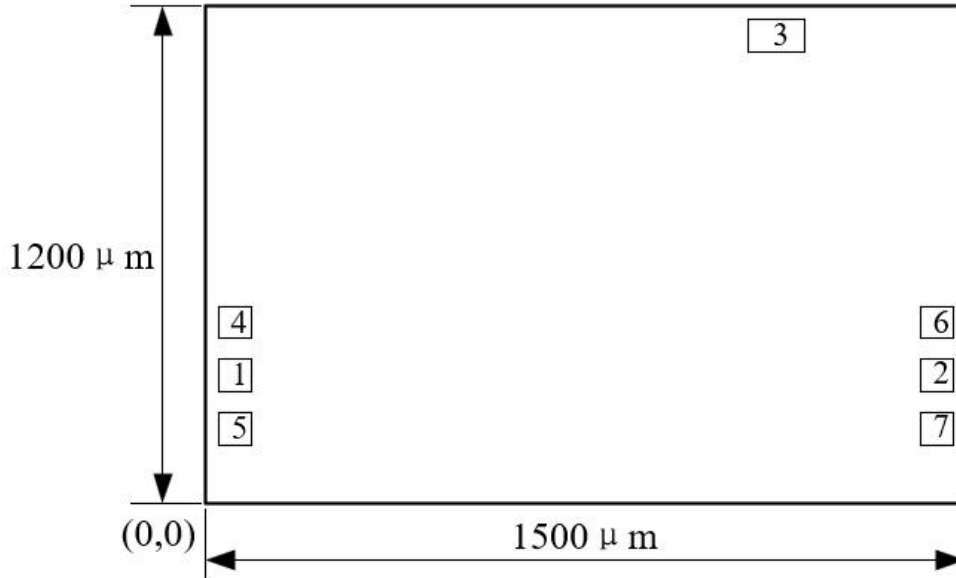
Parameter	Symbol	Min.	Typ.	Max.	Unit	Remarks (Conditions)
Drain Voltage	VD		5.0		V	
Operating Current	ID					
-55°C			107		mA	
+25°C			109		mA	
+85°C			108		mA	
+125°C			106		mA	

## 6. Absolute Maximum Ratings

All voltages are referenced to GND.

Parameter	数值
Drain Voltage VD	TBD
HBM ESD Rating	TBD
CDM ESD Rating	TBD
Max. Input Power (CW, 50 $\Omega$ , TA = 25 °C)	TBD
Thermal Resistance Rth	TBD
Channel Temperature TCH	175°C
Mounting Temperature (20 s, N2 protection)	320°C
Storage Temperature	-65°C ~ +150°C
Operating Temperature	-55°C ~ +125°C

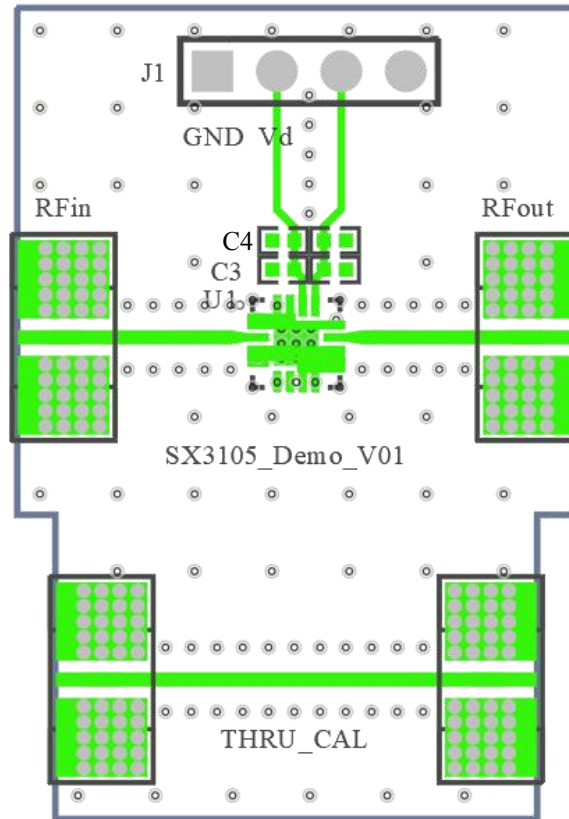
### 7. Package Dimensions



### 8. Pin Definitions

No.	Symbol	Attribute	PAD Size (μm)	PAD Position (μm)		Function Description
				X	Y	
1	RFin	Input	100×90	107.5	406	RF Signal Input Port
2	RFout	Output	100×90	1390.4	406	RF Signal Output Port
3	VD	Power	180×100	1058.2	1091.3	Drain Supply 5.0 V
4	GND	Ground	100×90	107.5	556	Ground
5	GND	Ground	100×90	107.5	256	Ground
6	GND	Ground	100×90	1390.4	556	Ground
7	GND	Ground	100×90	1390.4	256	Ground

## 9. Evaluation Demo Information



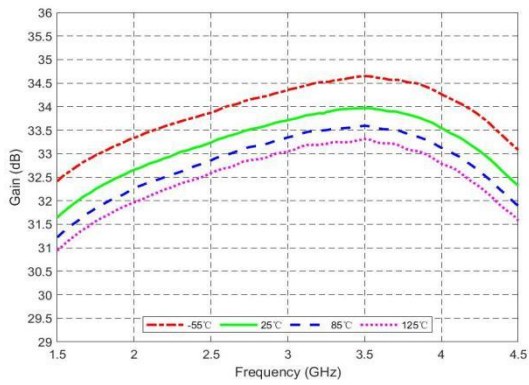
Pin	Description
RFin、RFout	RF signal input and output ports
J1	Drain supply +5.0 V
C3	0402C, 100 pF capacitor
C4	0402C, 1 μF capacitor

### 10. Test Curves

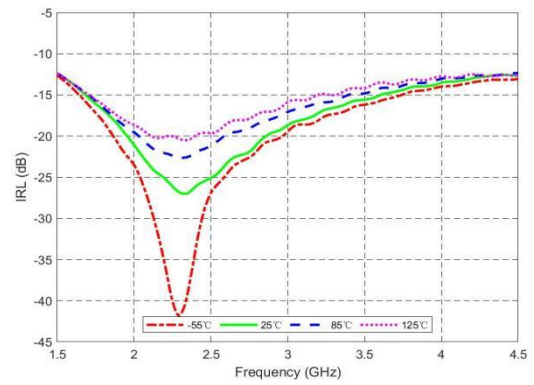
#### 10.1 Small Signal

Test conditions (unless otherwise specified):  $V_D = 5.0\text{ V}$ ,  $I_{DQ} = 109\text{ mA}$ ,  $P_{in} = -40\text{ dBm}$ ,  $T_A = +25\text{ }^\circ\text{C}$ ,  $50\text{ }\Omega$  system, continuous wave.

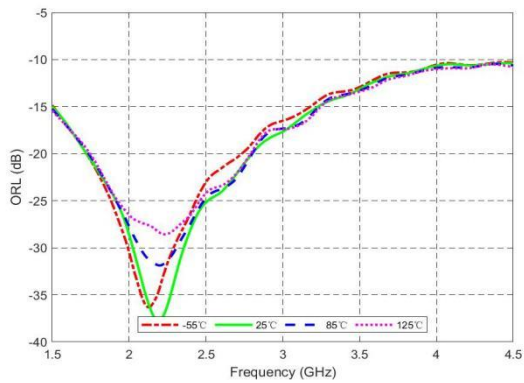
小信号增益 vs 频率 vs 温度



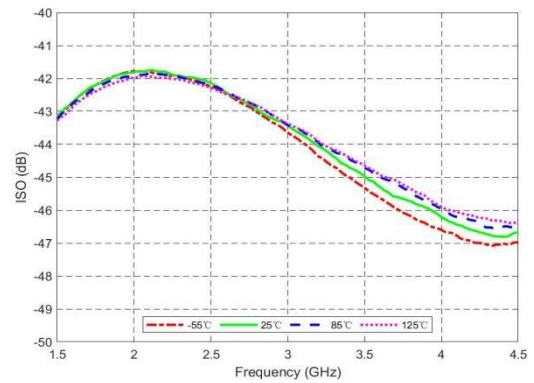
输入回波损耗 vs 频率 vs 温度



输出回波损耗 vs 频率 vs 温度



反向隔离度 vs 频率 vs 温度

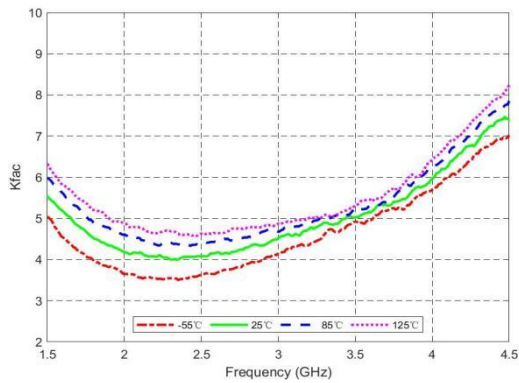


## 测试曲线

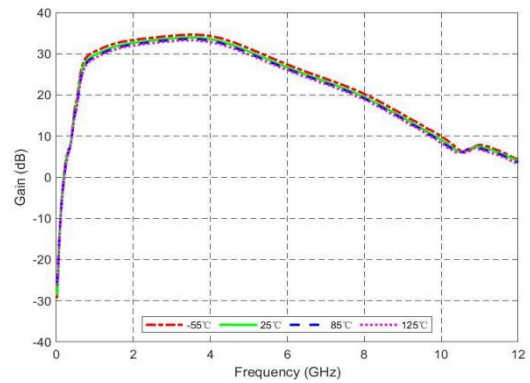
### 小信号

测试条件，除非特别说明：VD = 5.0V，IDQ = 109mA，Pin = -40dBm，TA = +25℃，50Ω系统，连续波。

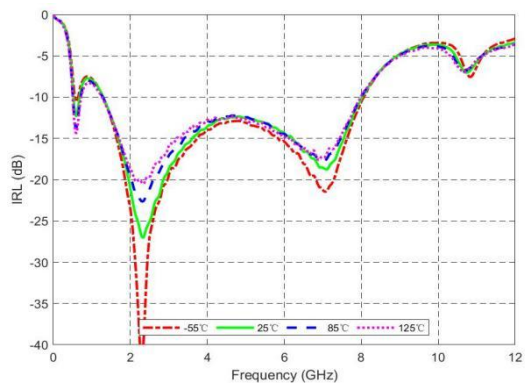
K 值 vs 频率 vs 温度



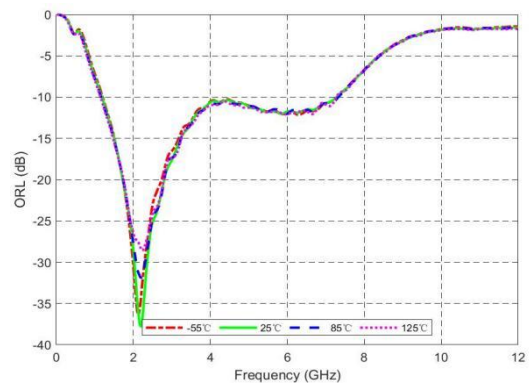
宽带小信号增益 vs 频率 vs 温度



宽带输入回波损耗 vs 频率 vs 温度



宽带输出回波损耗 vs 频率 vs 温度

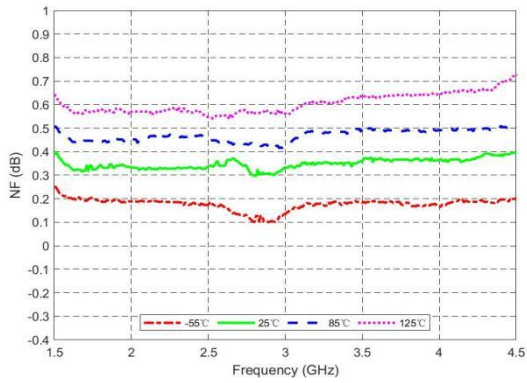


### 测试曲线

#### 10.2 Noise Figure

Test conditions (unless otherwise specified):  $V_D = 5.0\text{ V}$ ,  $I_{DQ} = 109\text{ mA}$ ,  $P_{in} = -40\text{ dBm}$ ,  $T_A = +25\text{ }^\circ\text{C}$ ,  $50\text{ }\Omega$  system, continuous wave.

噪声系数 vs 频率 vs 温度

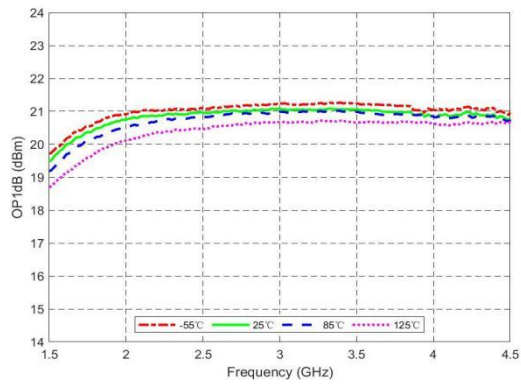


### Noise Figure vs Frequency vs Temperature

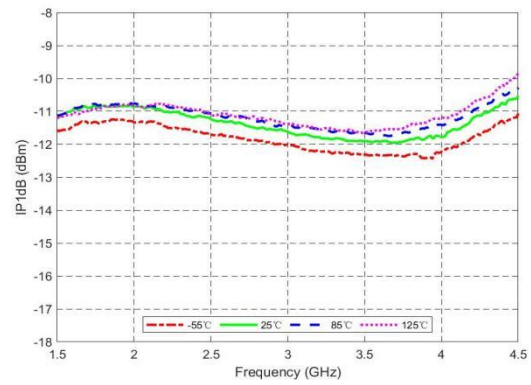
#### 10.3 Large Signal

Test conditions (unless otherwise specified):  $V_D = 5.0\text{ V}$ ,  $I_{DQ} = 109\text{ mA}$ ,  $T_A = +25\text{ }^\circ\text{C}$ ,  $50\text{ }\Omega$  system, continuous wave.

#### OP1dB vs Frequency vs Temperature

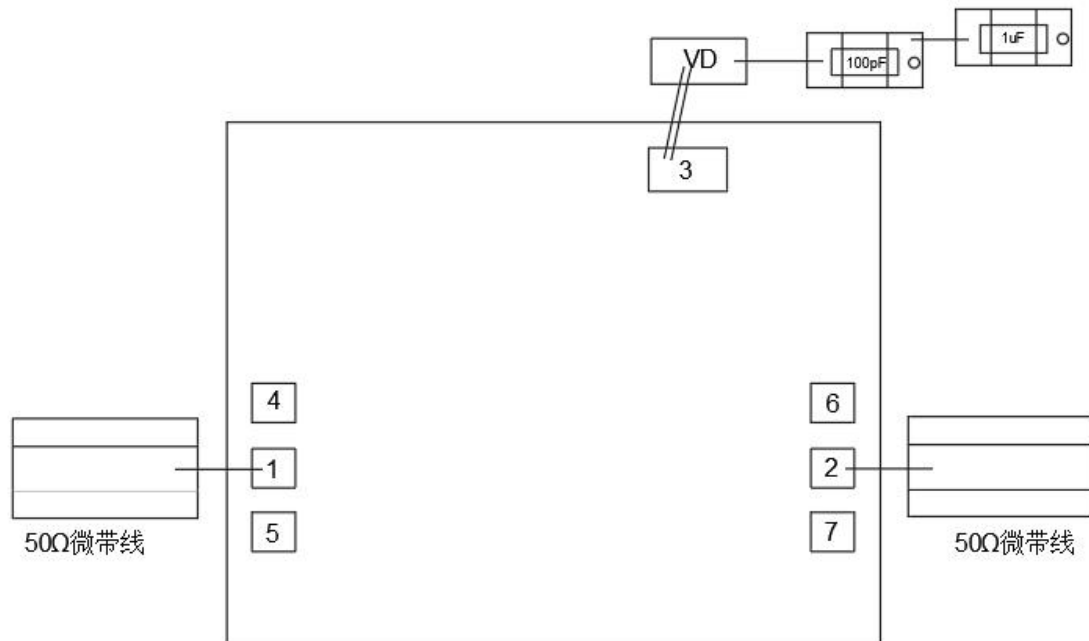


#### IP1dB vs Frequency vs Temperature



## 11. Application Information

### 11.1 Recommended Application Circuit



Note: Gold wire length at RF input: 650  $\mu\text{m}$ , RF output: 500  $\mu\text{m}$ , drain voltage: 600  $\mu\text{m}$ .

### 11.2 Operating Instructions

#### Power-on Sequence

1. Set current limit  $I_D$  to 200 mA.
2. Set  $V_D = +5.0\text{ V}$  and turn on;  $I_{DQ} \approx 109\text{ mA}$ .
3. Apply RF signal.

#### Power-off Sequence

1. Remove RF signal.
2. Set  $V_D$  to 0 V.
3. Turn off  $V_D$ .

### 11.3 Operating Protection Conditions



ESD (Electrostatic Discharge) sensitive device. Charged devices and printed circuit boards can discharge without detection. Although this product includes ESD protection circuits, high-energy ESD may cause device damage. Therefore, proper ESD precautions must be taken to avoid performance degradation or functional failure.

### 11.4 Operating Precautions

#### Chip Storage:

Chips must be stored in ESD-protective containers and under nitrogen atmosphere.

#### Cleaning:

Bare chips must be handled in a clean environment. Liquid cleaning agents are prohibited for chip cleaning.

#### ESD Protection:

Strictly follow ESD protection requirements to avoid electrostatic damage.

#### General Handling:

Use vacuum pick-up or precision sharp tweezers to handle chips. Avoid tool or finger contact with the chip surface.

#### Assembly:

Chip mounting can use Au80Sn20 eutectic solder or conductive adhesive. The mounting surface must be clean and flat.

1)**Eutectic Sintering:** Typically uses Au80Sn20 solder in inert (N<sub>2</sub>) atmosphere. Manual sintering: 290 °C~300 °C, ≤ 30 s. Automatic equipment: max. 320 °C.

2)**Adhesive Bonding:** Minimize conductive adhesive volume; visible adhesive around chip after placement. Follow curing specs from adhesive supplier.

**Bonding:** φ25 μm gold wire recommended for ball or wedge bonding. Hot plate: ~150 °C. Ball bonding force: 40~50 gf; wedge bonding: 18~22 gf. Bonding starts from chip pad to package/substrate. Package traces near I/O ports: 70 μm~150 μm. RF port wire length ≤ 300 μm.

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